


<b>Search Notes</b> 	<b>Application/Control No.</b> 10568581	<b>Applicant(s)/Patent Under Reexamination</b> PEYER, MARCO
	<b>Examiner</b> Ahshik Kim	<b>Art Unit</b> 2876

SEARCHED			
Class	Subclass	Date	Examiner
235	382	9/17/2009	ak
	382.5	9/17/2009	ak
705	75	9/17/2009	ak
	76	9/17/2009	ak

SEARCH NOTES		
Search Notes	Date	Examiner
See attached EAST search history	9/17/2009	ak

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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